

Advanced Test Equipment Rentals www.atecorp.com 800-404-ATEC (2832)

Portable Surface Roughness Tester SURFTEST SJ-410 Series



Bulletin No. 2080

Portable surface roughness tester evolution

Rich choice of options provide easier, smoother and more accurate measurements



Portable surface roughness tester evolves!

The large touch-screen, color-graphic LCD ensures both intuitive control and advanced operability

Enhanced power for making measurements on site

Color-graphic LCD

The color-graphic LCD with excellent visibility displays calculated results and assessed profiles even clearer. This is really useful for checking results without printing them out.

Backlight provided

A backlight improves usability in dim testing environments.

Touch screen for easier operations

The screen display can be switched between icon display and text display. Successfully combining operability with utility and usability.



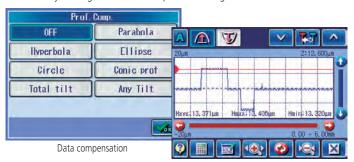


Icon display

Text display

Easy to use and highly functional

This portable surface roughness tester is equipped with analysis functionality rivaling that of benchtop surface roughness testers.



Simple contour analysis function

A wide range, high-resolution detector

SJ-412

SJ-411

Measuring range/ resolution 800µm/0.01µm 80μm/0.001μm 8µm/0.0001µm

High straightness drive unit

High accuracy measuring

Straightness/ traverse length 0.3µm/25mm (**SJ-411**) 0.5µm/50mm (SJ-412)



Applicable standards

1997, and ANSI

JIS1982

Complies with many industry standards The Surftest SJ-410 complies with the

following standards: JIS (JIS-B0601-2001,

JIS-B0601-1994, JIS B0601-1982), VDA, ISO-

JIS1994



The display interface supports 16 languages.



Multilingual support

Surftest SJ-410

Interfaces

A variety of interfaces supplied as standard

The external device interfaces that come as standard include USB, RS-232C, SPC output and footswitch I/F.



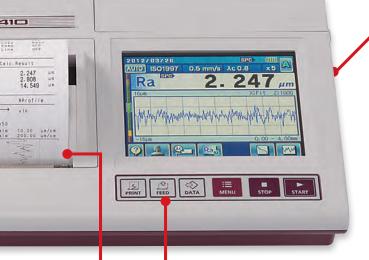
Data storage

Memory card (optional) is supported

The measurement conditions and data can be stored in a memory card (optional) and recalled as required. This enables batch analysis and printout of data after on-site measurement.



- •Measurement condition Internal memory: 10 sets Memory card: 500 sets
- •Measurement result
 Memory card: 1000 sets



Password protection

Access to functions can be restricted by a password

A pre-registered password can limit use of measurement conditions and other settings to the tester's administrator.



Key-sheet buttons

A sturdy key-sheet-button panel with superior durability in any environment is provided. For repeat measurement of the same work, simply pressing the start switch can complete measurement, analysis and printout.

Carrying case

The unit is easily transported in a dedicated carrying case which includes holders for the accessories as well as the tester itself. (Standard accessory.)



Printer

High-speed printer prints out measurement results on site

A high-quality, high-speed thermal printer prints out measurement results. It can also print a BAC curve or an ADC curve as well as calculated results and assessed profiles. These results and profiles are printed out in landscape format, just as they appear on the color-graphic LCD.



Enhanced measuring functions

Your choice of skidless or skidded measurement

Patent registered in Japan, U.S.A.. Patent pending in Germany

In skidded measurements, surface features are measured with reference

to a skid following close behind the stylus. This cannot measure

waviness and stepped features exactly but the range of movement

within which measurement can be made is greater because the skid

Skidless measurement

Skidless measurement is where surface features are measured relative to the drive unit reference surface. This measures waviness and finely stepped features accurately, in addition to surface roughnness, but range is limited to the stylus travel available. The SJ-410 series supports a variety of surface feature measurements simply by replacing the stylus.



Measuring example of stepped

Measured profile



Measuring example of stepped features: Skidded

Skidded measurement

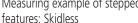
tracks the workpiece surface contour.

Measured profile

Fulcrum point of Stylus

Fulcrum point of Skid





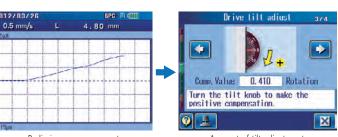


Patent registered in Japan, U.S.A.. Patent pending in Germany

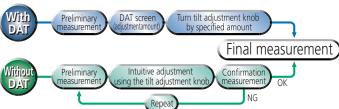
The height/tilt adjustment unit comes as standard for leveling the drive unit prior to making skidless measurements and, supported by guidance from the unique D.A.T. function, makes it easy to achieve highly accurate alignment.

Height/tilt adjustment unit (Standard accessory)





Amount of tilt adjustment



When the SJ-410 Series detector is mounted on the manual column stand*1 for measurement, it can be combined with any of the optional products for easier leveling: leveling table*1, 3-axis alignment table*1 or tilt adjustment unit*1. *1: For details about optional products, see P6-7.



More measuring functions than expected from a compact tester

Usually, a spherical or cylindrical surface (R-surface) cannot be evaluated, but, by removing the radius with a filter, R-surface data is processed as if taken from a flat surface.





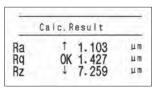
Recalculating

Previously measured data can be recalculated for use in other evaluations by changing the current standard, assessed profile and roughness parameters.

GO/NG judgement function

An "OK/NG" judgment symbol is displayed when limits are set for the roughness parameter. In case of "NG," the calculated result is highlighted. The calculated result can also be printed out.



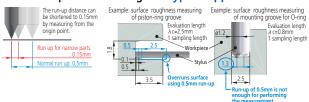


The "OK" symbol means the measurement is within the limits set; "NG" means it is not, in which case an arrow points to either the upper or lower limit in the printout.

Narrow space measuring function Patent pending in Japan

Surface roughness measurement requires a run-up distance before starting the measurement (or retrieving data). When the SJ-410 Series measures, its run-up distance is normally set to 0.5mm. This distance, however, can be shortened to 0.15mm using the narrow part measurement function (starting from the origin point of the drive unit). The function extends the possibility of measurement of narrow locations such as grooves in piston ring / O-ring mounts.

Narrow space measuring Typical applications



Real sampling

This function samples stylus displacement for a specified time without engaging detector traverse, which enables use as a simplified vibration meter or displacement gage incorporated in another system.

Assessing a single measurement result under two different evaluation conditions

A single measurement enables simultaneous analysis under two different evaluation conditions. A single measurement allows calculation of parameters and analysis of assessed profiles without the need for recalculation after saving data, contributing to higher work efficiency.



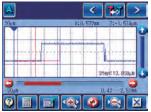


Arbitrary sampling length setting

This function allows a sampling length to be arbitrarily set in 0.01mm increments (**SJ-411**: 0.1mm to 25mm, **SJ-412**: 0.1mm to 50mm). It also allows the **SJ-410** series to make both narrow and wide range measurements.

Simple contour analysis function

Point group data collected for surface roughness evaluation is used to perform simplified contour analysis (step, step height, area and coordinate variation). It assesses minute forms that cannot be assessed by a contour measurer.









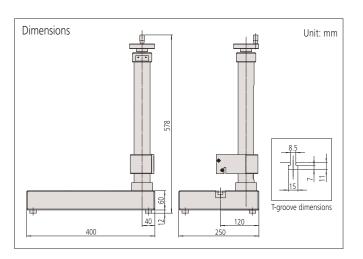
Dimensions Coordinate difference

Optional Accessories

Simple column stand

Can be adjusted to match the height of the item to be measured.





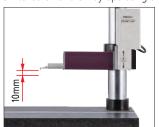
Options for simple column stand

Three new optional products are available to be attached to the manual column stand (**No.178-039**). You can choose the unit that suits your application. Or, you can also use the three products in any combination. Using the optional units makes **SJ-411/412** more convenient and easier to use to ensure accurate measurements.

Auto-set unit (178-010)*

This unit enables the vertical (Z axis) direction to be positioned automatically (auto-set function).

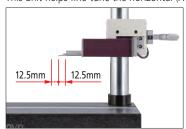
A single button operation completes a series of operations from measurement, saving and auto-return (saving and auto-return can be switched on and off by operating the drive unit).





X-axis adjustment unit (178-020)*

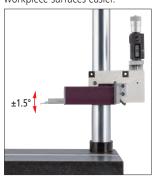
This unit helps fine-tune the horizontal (X axis) direction.





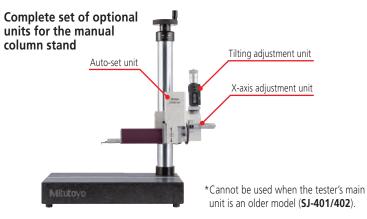
• Tilting adjustment unit (178-030)*

This unit is used for aligning the workpiece surface with the detector reference plane. It supports the DAT function to make the leveling of workpiece surfaces easier.





Tilt adjustment

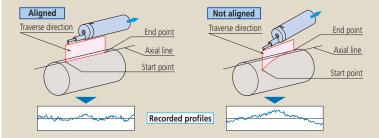


3-axis Adjustment Table: 178-047

Patent registered in Japan, U.S.A.. Patent pending in Germany

This table helps make the alignment adjustments required when measuring cylindrical surfaces. The corrections for the pitch angle and the swivel angle are determined from a preliminary measurement and the Digimatic micrometers are adjusted accordingly. A flat-surfaced workpiece can also be leveled with this table.





DAT Function for the optional leveling table

Patent registered in Japan, U.S.A.. Patent pending in Germany

The levelling table can be used to align the surface to be tested with the detector reference plane. The operator is guided through the procedure by screen prompts.



No.178-048 Inclination adjustment angle: ±1.5° Table dimensions: 130×100mm

Maximum load: 15kg



DAT screen guides the user when leveling Digimatic micrometer

Amount of micrometer head adjustment required

Leveling table (DAT)
(Option)



XY leveling tables

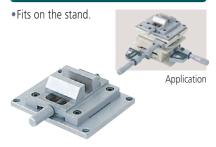
The tester includes X- and Y-axes micrometer heads. This makes axis alignment much easier because the tilt adjustment center is the same as the rotation center of the table. (Code No.178-042-1/178-043-1)







Precision vise



Order No.	178-019
Clamping method	Sliding jaws
Jaw opening	36mm
Jaw width	44mm
Jaw depth	16mm
Height	38mm

Cylinder attachment

This block can be positioned on top of cylindrical objects to perform measurements.

No.12AAB358

Diameter: ø15~60mm

Configuration:

- •Cylindrical measurement block
- Auxiliary block
- Clamp
- *Drive unit not included.

Reference step specimen

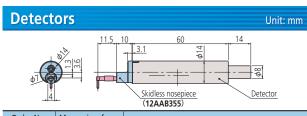
Used to calibrate detector sensitivity.

No.178-611

Step nominal values: 2µm/10µm

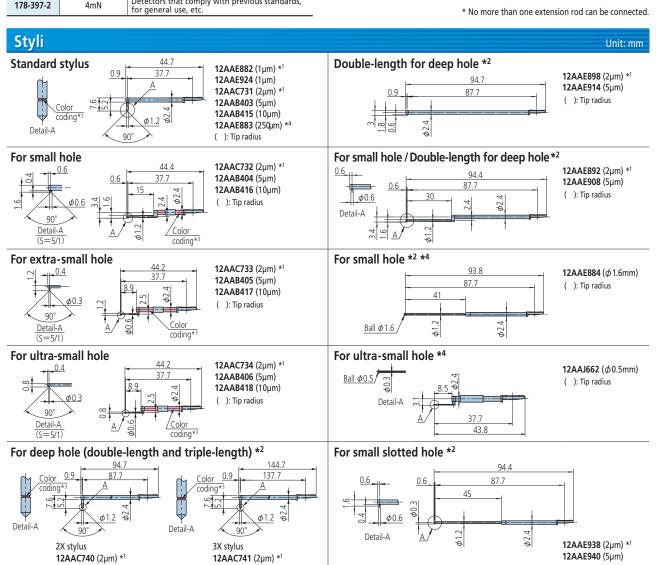


Optional Accessories: Detectors / Styli



Order No.	Measuring force	
178-396-2	0.75mN	ISO-1997 and JIS-2001 compliant detectors
178-397-2	4mN	Detectors that comply with previous standards, for general use, etc.

• 12AAG202 Extension rod 50mm • 12AAG203 Extension rod 100mm



*1: Tip angle 60°

(): Tip radius

12AAB413 (5μm) 12AAB425 (10μm) (): Tip radius



^{*4:} Used for calibration, a standard step gauge (No.178-611, option) is also required

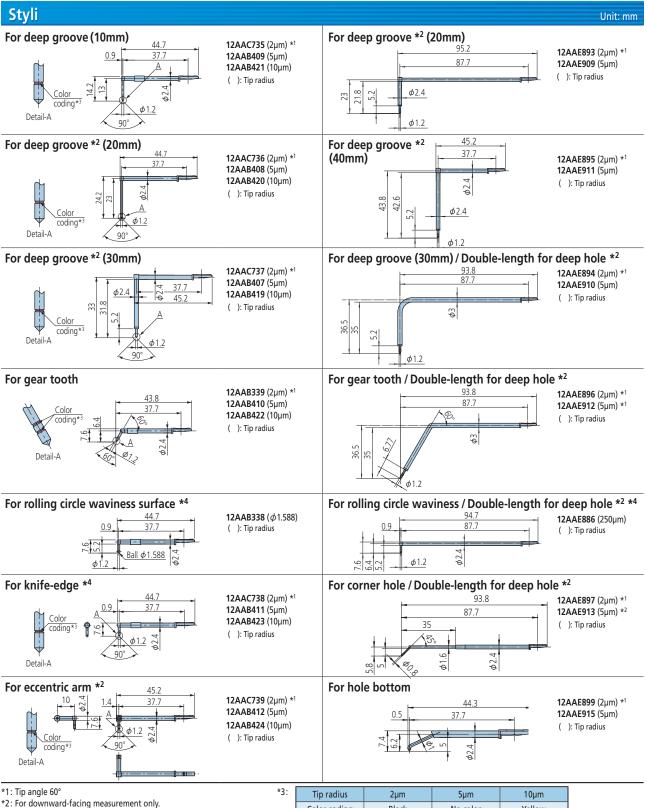
12AAB414 (5µm)

^{*2:} For downward-facing measurement only.

 ¹²AAB426 (10µm)
 (): Tip radius

 *3:
 Tip radius
 1µm
 2µm
 5µm
 10µm
 250µm

 Color coding
 White
 Black
 No color
 Yellow
 No notch or color



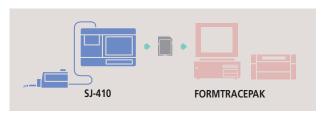
^{*}Customized special interchageable styli are available on request, Please contact any Mitutoyo office for more information.

Tip radius $2\mu m$ 5µm 10µm Color coding Black No color Yellow

Optional Accessories: For External Output

Contour / Roughness analysis software FORMTRACEPAK

More advanced analysis can be performed by loading SJ-410 series measurement data to software program FORMTRACEPAK via a memory card (option) for processing back at base.



Digimatic mini processor DP-1VR

By connecting this printer to the Surftest SJ-410's digimatic output, you can print calculation results, perform a variety of statistical analyses, draw a histogram or D chart, and also perform complicated operations for X-R control charts.



Measurement Data Wireless Communication System U-WAVE

This unit allows you to remotely load Surftest SJ-410 calculation results (SPC output) into commercial spreadsheet software on a PC. You can essentially use a one-touch operation to enter the calculation results (values) into the cells in the spreadsheet software.



U-WAVE-R (Connects to the PC) No.02AZD810D



U-WAVE-T * (Connects to the SJ-410) No.02AZD880D

*Requires the optional Surftest SJ-410 connection cable.

No.02AZD790D



Simplified communication program for SURFTEST SJ series

The Surftest SJ-410 series has a USB interface, enabling data to be transferred to a spreadsheet or other software.

We also provide a program that lets you create inspection record tables using a Microsoft Excel* macro.

This program can be downloaded free of charge from the Mitutoyo website.

http://www.mitutoyo.co.jp

Required environment*

 OS: Windows XP-SP3 Windows Vista Windows 7 • Spreadsheet software: Microsoft Excel 2002 Microsoft Excel 2003 Microsoft Excel 2007 Microsoft Excel 2010

*Windows OS and Microsoft Excel are products of Microsoft Corporation.

The optional USB cable is also required.

• USB cable for SJ-410 series No.12AAD510

Calculation results input unit INPUT TOOL

This unit allows you to load Surftest SJ-410 calculation results (SPC output) into commercial spreadsheet software on a PC via a USB connector. You can essentially use a one-touch operation to enter the calculation results (values) into the cells in the spreadsheet software.



USB-ITN-D No.06ADV380D



USB keyboard signal conversion type*
IT-012U
No.264-012-10

*Requires the optional Surftest SJ-410 connection cable.

1m: No.936937 2m: No.965014

Optional accessories, consumables, and others for SJ-410

Printer paper (5 rolls)
 Durable printer paper (5 rolls)
 No.270732
 No.12AAA876

• Touch-screen protector sheet (10 sheets)

No.12AAN040 No.12AAL069

Memory card (2GB) *

No.12AAL069 No.12AAA882

Connecting cable (for RS-232C)

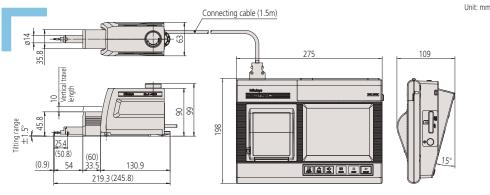
*micro SD card (with a conversion adapter to SD card)

Specifications

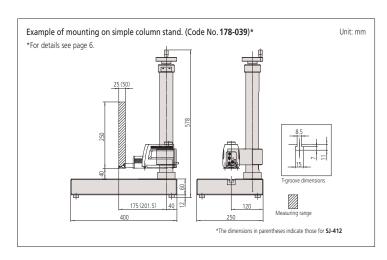
Model No.		SJ-4	111			SJ-	412		
	inch/mm	178-581-01A	178-581	-02A	178-583-01A			178-583-02A	
Measuring	X axis	25mm	(1inch)			50mm	(2inch)		
range	Z1 axis (detector unit)	800µm, 80µm, 8µm *Up to 2,400µm with an optional stylus							
	Measuring principle	Differential inductance							
	Resolution	0.01µm (800µm range) / 0.001µm (80µm range) / 0.0001µm (8µm range) 0.4µinch (32000µinch) / 0.04µinch (3200µinch) / 0.004µinch (320µinch)							
Detector	Stylus tip	60°/2μm (80μinch) 90°/5μm (200μinc		00µinch)	60°/2μm (80μinch) 90°/5μm (200μinch)				
	Measuring force	0.75mN 4mN		1	0.75mN		4mN		
	Radius of skid curvature	R40 mm (R1.57")							
	Measuring method	Skidded measurement / skidless measurement							
	Measuring speed	0.05, 0.1, 0.2, 0.5, 1.0mm/s (0.002, 0.004, 0.02, 0.04 inch/s)							
Orive unit: X-axis	Drive speed	0.5 , 1, 2 , 5mm/s (0.02 , 0.04 , 0.08 , 0.2 inch/s)							
	Straightness	0.3μm / 25mm (12μinch/ 1inch) 0.5μm / 50mm (20μinch/ 2inch) 10mm (0.39inch)					h/ 2inch)		
leight-tilt	Height adjustment								
idjustment unit	Tilt adjustment		UC1002 / I	±1.		D A			
Standards		D- D- D- D- D- D- D- D- D-	JIS 1982 / JI	15 1994 / JIS200	1 / ISO1997 / ANSI / VI	JA -IIC+3 D	-: D	D.A. o. Dla Dava Dava(a)	
Parameters		Ra, Rq, Rz, Ry, Rp, Rv, Rt, R3z, Rsk, Rku, Rc, RPc, RSm, Rmax*¹, Rz1max*², S, HSC, RzJIS*³, Rppi, RΔa, RΔq, Rlr, Rmr, Rmr(c), Rσc, Rk, Rpk, Rvk, Mr1, Mr2, A1, A2, Vo, λa, λq, Lo, Rpm, tp*4, Htp*4, R, Rx, AR, W, AW, Wx, Wte, Possible Customize							
Measured profiles		Pr	imary Roughness	DE Filtered w	vaviness curve, R-Mot	if \\/_\/\	tif	r, russible Custofflize	
Graph analysis			mary, Nougriness	BAC and A		.11, ۷۷-1۷10	uii		
Data compensatio	ın	Par	ahola/ Hynerhola		Conic/ Tilting, Com	nensation	off		
ilter		Ture	ibola/ Tryperbola/	2CR, PC75, G		JC113G (101	OII		
	λς			0.08, 0.25, 0.8					
Cut-off length	λs *5				0, 320, 1000µinch)				
ample length	,,,,	0.08, 0.25, 0.8, 2.5, 8.0, 25.0mm							
Number of sampli	na lenaths	x1, x2, x3, x4, x5, x6, x7, x8, x9, x10, x11, x12, x13, x14, x15, x16, x17, x18, x19, x20							
Arbitrary length		0.1~25mm 0.1~50mm							
	Customization		Desired paramete	ers can be selec	ted for calculation a	nd display	/		
	Simple contour analysis function				ons, Coordinate diffe				
	DAT function				ing skidless measure				
	Real sampling function	Samples stylus displacement for a specified time without engaging detector traverse.							
	Statistical processing	Static measurement (max. 3 parameters) is possible. Static processing for MAX, MIN, AVERAGE, standard deviation, histogram and pass rate is possible							
	GO/ NG judgement*6	Max rule / 16% rule / Average rule / Standard deviation (1 σ , 2 σ , 3 σ)							
unctions	Storage functions	10 measuring conditions can be stored in internal memory							
anctions	Printing function	Measurement conditions / Calculation results / GO / NG judgement result / Calculation results for each sampling length / Measurement curve / BAC / ADC / Environmental setting information							
	Display languages	Japanese, English, German, French, Italian, Spanish, Portuguese, Korean, Traditional Chinese, Simplified Chinese, Czech, Polish, Hungarian Turkish, Swedish, Dutch							
-	Storage	Internal memory: Measurement condition (10 sets) Memory card (option): 500 measurement condition, 10000 measuring data, 10000 text data, 500 statistic data, 1 backup of machine setting, the last ten traces (Trace 10)							
	External I/O	USB I/F, Digimatic output, RS-232C I/F, External SW I/F							
		Two-way power supply: battery (rechargeable Ni-MH battery) and AC adapter							
Dower cupply	Battery	*Charging time: about 4 hours (may vary due to ambient temperature)							
ower supply		*Endurance: about 1500 measurements (differs slightly due to use conditions / environment)							
	Power consumption	50W							
ize	Display unit	275×198×109mm (10.83×4.29×7.80inch)							
WxDxH)	Height adjustment unit	130.9×63×99mm (5.16×2.48×3.90 inch)							
	Drive unit	128×35.8×46.6mm (5	5.04×1.41×1.83 i	- /		<46.6mm	(6.08×	1.41×1.83inch)	
	Display unit			1.7					
∕lass	Height adjustment unit	0.4kg							
	Drive unit	0.6					4kg	1.	
Standard accessor	ies	Detector* ⁷ , Stylus* ⁸ , Rough 270732 Printing paper 12BAL402 Touch-screen		12BAG834 12AAN041	Touch pen Sti	ap for sty	lus pen,	screwdriver, Operation manual, nual, Warranty	

^{*1:} Only for VDA/ANSI/JIS'82 standards.
*2: Only for JIS'97 standard.
*3: Only for JIS'01 standard.
*4: Only for ANSI standard.

^{*5: 3}s may not be switchable depending on standard selected.
*6: Standard deviation only can be selected in ANSI.16% rule cannot be selected in VDA.
*7: Either No.178-396-2 or No.178-397-2 is supplied as a standard accessory depending on the Order No. of the main unit for SJ-410 Series.
*8: The standard stylus (No.12AAC731 or No.12AAB403), which is compatible with the detector supplied, is a standard accessory.



*The dimensions in parentheses indicate those for SJ-412



Note: All information regarding our products, and in particular the illustrations, drawings, dimensional and performance data contained in this printed matter as well as other technical data are to be regarded as approximate average values. We therefore reserve the right to make changes to the corresponding designs. The stated standards, similar technical regulations, descriptions and illustrations of the products were valid at the time of printing. In addition, the latest applicable version of our General Trading Conditions will apply. Only quotations submitted by ourselves may be regarded as definitive.

Mitutoyo products are subject to US Export Administration Regulations (EAR). Re-export or relocation of our products may require prior approval by an appropriate governing authority.

Trademarks and Registrations

Designations used by companies to distinguish their products are often claimed as trademarks. In all instances where Mitutoyo America Corporation is aware of a claim, the product names appear in initial capital or all capital letters. The appropriate companies should be contacted for more complete trademark and registration information.

Coordinate Measuring Machines

Vision Measuring Systems

Form Measurement

Optical Measuring

Sensor Systems

Test Equipment and Seismometers

Digital Scale and DRO Systems

Small Tool Instruments and Data Management

Mitutoyo America Corporation

www.mitutoyo.com

One Number to Serve You Better 1-888-MITUTOYO (1-888-648-8869)

M³Solution Centers Aurora, Illinois

(Corporate Headquarters)

Westford, Massachusetts

Huntersville, North Carolina

Mason, Ohio

Plymouth, Michigan

City of Industry, California

Birmingham, Alabama

